

**Search Notes**

Application/Control No.

10/004,064

Examiner

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Applicant(s)/Patent under  
Reexamination

NEWMAN ET AL.

Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
708	131, 141	6/21/2005	MAI
341	20-35	6/21/2005	↓
704	246	6/21/2005	

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search Double Patenting Check Data Bases Search (see attached copy)	6/21/2005	MAI